

THOMSON SEMICONDUCTORS

TLF 1006 → TLF 4006
FAST SWITCHING
ASYMMETRICAL THYRISTORS
THYRISTORS RAPIDES
ASYMETRIQUES

K 78C 07746 D
 T-25-13

- High frequency applications.
- V_{DRM} up to 400 V.
- Glass passivated chip - High stability and reliability.
- High surge capability.

- Applications hautes fréquences.
- V_{DRM} jusqu'à 400 V.
- Pastille glassivée - Grande stabilité des caractéristiques.
- Courant de surcharge élevé.

$$I_{T(RMS)} = 3 \text{ A} / T_L = 50^\circ\text{C}$$

$$V_{DRM} \\ 100 \text{ V} < = < 400 \text{ V}$$

$$V_{RRM} \\ t_q < 15 \mu\text{s}$$

Case : TL (CB-274) plastic
 Boîtier



ABSOLUTE RATINGS (LIMITING VALUES) VALEURS LIMITEES ABSOLUES D'UTILISATION	Symbol	Value	Unit
RMS on-state current* Courant efficace à l'état passant*	$I_{T(RMS)}$	3 @ $T_L = 50^\circ\text{C}$	A
Mean on-state current* Courant moyen à l'état passant*	$I_{T(AV)}$	2 @ $T_L = 50^\circ\text{C}$	A
Non repetitive surge peak on-state current** Courant non répétitif de surcharge crête accidentelle à l'état passant**	I_{TSM} I_{TSM}	52,5 (t = 8,3 ms) 50 (t = 10 ms) @ $T_j < 110^\circ\text{C}$	A A
I^2t for fusing Valeur de la constante I^2t	I^2t	12,5 (t = 10 ms) @ $T_j < 110^\circ\text{C}$	A ² s
Critical rate of rise of on-state current*** Vitesse critique de croissance du courant à l'état passant***	di/dt	100	A/ μs
Storage and operating junction temperatures Températures extrêmes de stockage et de jonction en fonctionnement	T_{stg} T_j	- 40, + 150 - 40, + 110	$^\circ\text{C}$ $^\circ\text{C}$

@ $T_j = 110^\circ\text{C}$	TLF 1006	TLF 2006	TLF 3006	TLF 4006
V_{DRM} (V)	100	200	300	400
V_{RRM} (V)	5	5	5	5

Thermal resistances Résistances thermiques	Symbol	Value	Unit
- Junction-leads Jonction-connexions	$R_{th(j-l)}$	15	$^\circ\text{C}/\text{W}$
- Junction-ambient on printed circuit (with Cu 1 cm ²) Jonction-ambiante sur circuit imprimé (avec Cu 1 cm ²)	$R_{th(j-a)}$	50	$^\circ\text{C}/\text{W}$

*Single phase circuit, 180° conduction angle
 *Circuit monophasé, angle de conduction 180°
 *** $I_{GT} = 100 \text{ mA}$, di/dt = 1 A/ μs

**Half-sine wave
 **Demi-onde sinusoïdale

July 1984 - 1/4

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183

THOMSON
 COMPONENTS

TLF 1006 → TLF 4006

78C 07747 D

T-25-13

GATE CHARACTERISTICS (Maximum values)
CARACTERISTIQUES DE GACHETTE (Valeurs maximales)

PGM = 20 W (t = 10 μs)
 PG(AV) = 0,1 W

IFGM = 1 A (t = 10 μs)
 VFGM = 15 V (t = 10 μs)

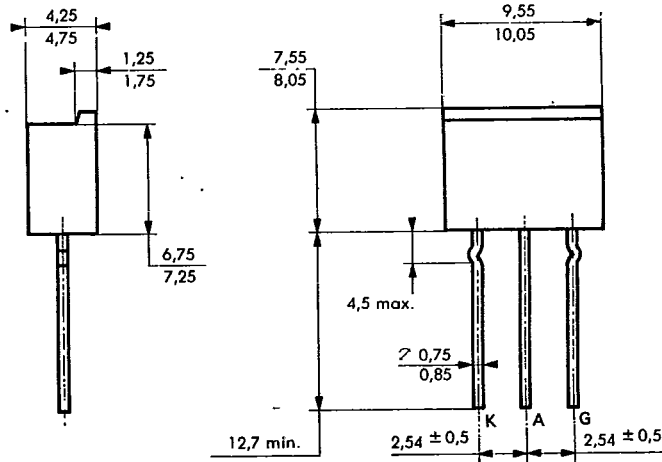
VRGM = 5 V

ELECTRICAL CHARACTERISTICS
CARACTERISTIQUES ELECTRIQUES

Symbol	Value			Unit	Test conditions			
	min	typ	max					
IGT			50	mA	T _j = 25°C	V _D = 12 V	R _L = 33 Ω	t _p ≥ 20 μs
VGT			2	V	T _j = 25°C	V _D = 12 V	R _L = 33 Ω	t _p ≥ 20 μs
VGD	0,2			V	T _j = 110°C	V _D = V _{DRM}	R _L = 3,3 kΩ	
I _H		30		mA	T _j = 25°C	I _T = 100 mA	Gate open	
V _{TM}			2,2	V	T _j = 25°C	I _{TM} = 6 A	t _p = 10 ms	
I _{DRM}			1	mA	T _j = 110°C	V _{DRM} specified		
I _{RRM}			1	mA	T _j = 110°C	V _{RRM} specified		
t _{gt}		1		μs	T _j = 25°C I _G = 100 mA	I _T = 6 A di _G /dt = 1 A/μs	V _D = V _{DRM}	
t _q			15	μs	T _j = 110°C di _R /dt = 30 A/μs	I _T = 5 A dv/dt = 100 V/μs	V _R = -1 V	V _D = 0,67 V _{DRM} Gate open
dv/dt*	100			V/μs	T _j = 110°C	Linear slope up to 0,67 V _{DRM} specified Gate open		

*For higher guaranteed values, please consult us.

CASE DESCRIPTION
DESCRIPTION DU BOITIER



Cooling method : by convection (method A)
 Marking : type number
 Weight : 0,8 g

TL (CB-274) plastic

T-25-13

78C 07748

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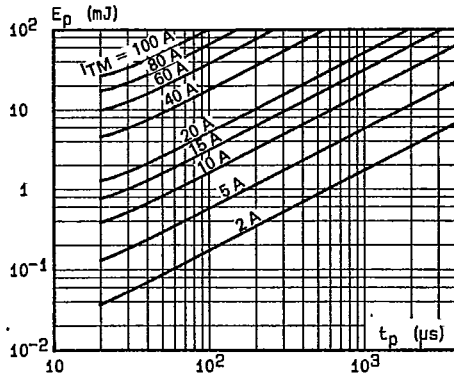


Fig.1 - Energy per pulse for sinusoidal pulses.

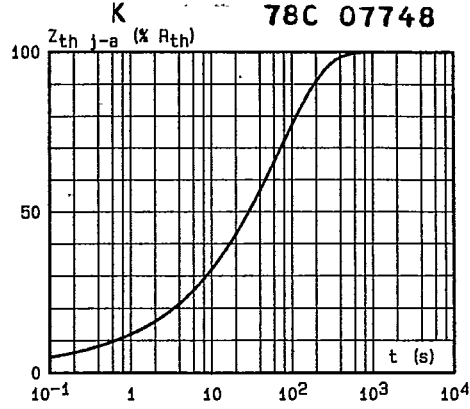
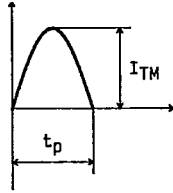


Fig.2 - Thermal transient impedance junction to ambient versus pulse duration.

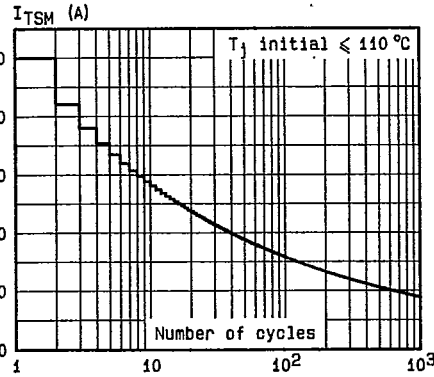
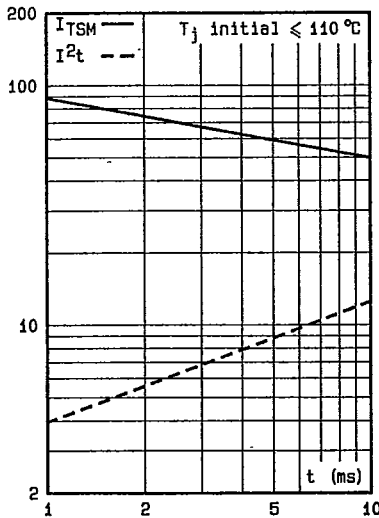


Fig.3 - Non repetitive surge peak on-state current versus number of cycles.

Fig.4 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

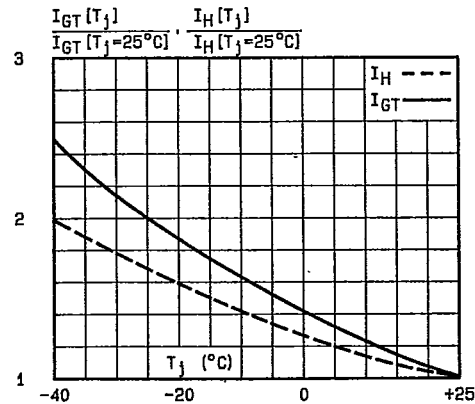


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

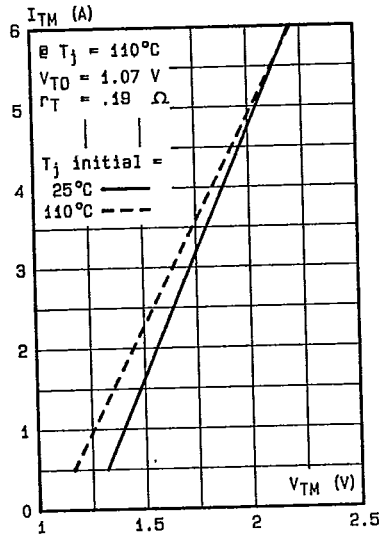


Fig.6 - On-state characteristics at low level (maximum values).

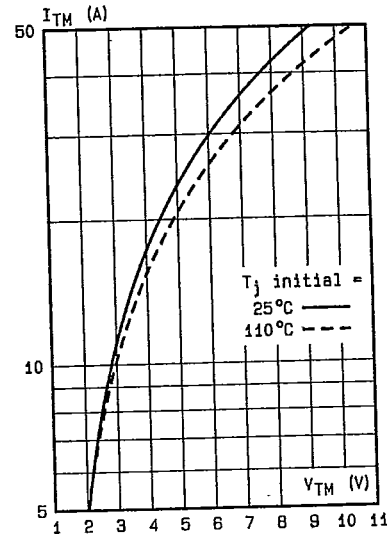


Fig.7 - On-state characteristics at high level (maximum values).